Ignition IGBT

PD - 94060

Die in Wafer Form

IRGC14C40LB IRGC14C40LC IRGC14C40LD

IGBT with on-chip Gate-Emitter and Gate-Collector clamps

Features

- Most Rugged in Industry
- •Logic-Level Gate Drive
- > 6KV ESD Gate Protection

International

ICR Rectifier

- Low Saturation Voltage
- High Self-clamped Inductive Switching Energy
- •Qualified for the Automotive Qualified [Q101] .

Description

The advanced IGBT process family includes a MOS gated, N-channel logic level device which is intended for coil-on-plug automotive ignition applications and small-engine ignition circuits. Unique features include on-chip active voltage clamps between the Gate-Emitter and Gate-Collector which provide over voltage protection capability in ignition circuits.

NOTES: 1) Part number IRGC14C40LB are die in wafer form probed and uncut; IRGC14C40LC are die on film probed and cut; and IRGC14C40LD are probed die in wafle pack. 2) Reference packaged parts are IRGS14C40L, IRGSL14C40L, and IRGB14C40L.





Electrical Characteristics (Wafer Form)

Description	Guaranteed (min, max)	Test Conditions @ T _J = 25°C
Collector-to-Emitter Saturation Voltage	2.65V max	$I_{C} = 10A, V_{GE} = 4.5V$
Colletor-to-Emitter Breakdown Voltage	370V min, 430V max	R_G = 1K ohm, I_{CES} = 25mA, V_{GE} = 0V
Gate Threshold Voltage	1.2V min, 2.4V max	$V_{GE} = V_{CE}$, $I_C = 1mA$
Zero Gate Voltage Collector Current	10µA max	$R_G = 1K \text{ ohm}, V_{CE} = 300V$
Gate-to-Emitter Leakage Current	±0.32mA min, ±1mA max	V _{GE} = +/-10V
Operating Junction and Storage	-	40°C to 175°C
	Description Collector-to-Emitter Saturation Voltage Colletor-to-Emitter Breakdown Voltage Gate Threshold Voltage Zero Gate Voltage Collector Current Gate-to-Emitter Leakage Current Operating Junction and Storage Temperature Range	DescriptionGuaranteed (min, max)Collector-to-Emitter Saturation Voltage2.65V maxColletor-to-Emitter Breakdown Voltage370V min, 430V maxGate Threshold Voltage1.2V min, 2.4V maxZero Gate Voltage Collector Current10µA maxGate-to-Emitter Leakage Current±0.32mA min, ±1mA maxOperating Junction and StorageTemperature Range

Mechanical Data

Cr - Ni/V - Ag, (0.1µm - 0.2µm - 0.25µm)	
99% Al/1% Si, (4µm)	
0.141" x 0.164"	
150mm, with std. < 100 > flat	
.015" +/003"	
01-5467	
100µm	
0.25mm diameter minimum	
Consistent throughout same wafer lot	
Store in original container, in dessicated	
nitrogen, with no contamination	
For optimum electrical results, die attach	
temperature should not exceed 300°C	

Die Outline

